

STD70N03L STD70N03L-1

N-channel 30V - 0.0059Ω - 70A - DPAK / IPAK STripFET™ III Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STD70N03L	30V	<0.0073Ω	70A
STD70N03L-1	30V	<0.0073Ω	70A

- R_{DS(ON)} * Qg industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

Description

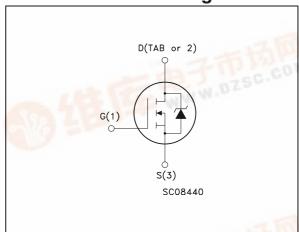
This product utilizes the latest advanced design rules of ST's proprietary STripFET™ technology. This is suitable for the most demanding DC-DC converter application where high efficiency is to be achieved.

Applications

Switching application



Internal schematic diagram



Order codes

Marking	Package	Packaging
D70N03L	DPAK	Tape & reel
D70N03L-1	IPAK	Tube
	D70N03L	D70N03L DPAK

Contents

1	Electrical ratings	3
2	Electrical characteristics	4
	2.1 Electrical characteristics (curves)	٠ ٤
3	Test circuit	10
4	Package mechanical data	11
5	Packaging mechanical data	14
6	Revision history	15

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	30	V
V _{GS}	Gate-source voltage	± 20	V
I _D	Drain current (continuous) at T _C = 25°C	70	Α
I _D	Drain current (continuous) at T _C = 100°C	50	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	280	Α
P _{TOT}	Total dissipation at T _C = 25°C	70	W
	Derating factor	0.47	W/°C
E _{AS} (2)	Single pulse avalanche energy	300	mJ
T _j T _{stg}	Operating junction temperature Storage temperature	-55 to 175	°C

^{1.} Pulse width limited by safe operating area

Table 2. Thermal resistance

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case Max	2.14	°C/W
Rthj-amb	Thermal resistance junction-amb Max	100	°C/W
T _I	Maximum lead temperature for soldering purpose	275	°C

^{2.} Starting Tj = 25° C, Id = 30A, Vdd = 15V

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table 3. On/off states

Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250 \mu A, V_{GS} = 0$	30			٧
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 20V, V _{DS} = 20V,Tc = 125°C			1 10	μ Α μ Α
I _{GSS}	Gate body leakage current(V _{DS} = 0)	V _{GS} = ±20V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1			٧
R _{DS(on)}	Static drain-source on resistance	V_{GS} = 10V, I_D = 35A V_{GS} = 5V, I_D = 35A V_{GS} = 10V, I_D = 35A @Tj=125°C V_{GS} = 5V, I_D = 35A @Tj=125°C		0.0059 0.007 0.0091 0.0108	0.0073 0.013 0.0113 0.0201	Ω Ω Ω

Table 4. Dynamic

Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	V _{DS} =10V, I _D = 15A		40		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25V, f=1MHz, V _{GS} =0		2200 380 49		pF pF pF
$egin{array}{c} Q_{ m g} \ Q_{ m gd} \end{array}$	Total gate charge Gate-source charge Gate-drain charge	V_{DD} =15V, I_{D} = 70A V_{GS} =5V (see Figure 7)		15.7 8.3 3.4	21	nC nC nC
Q _{gls} (2)	Third-quadrant gate charge	V _{DS} <0V, V _{GS} =10V		15		nC
R _G	Gate input resistance	f=1MHz Gate DC Bias =0 Test signal level =20mV open drain		1.5		Ω

^{1.} Pulsed: pulse duration = 300µs, duty cycle 1.5%

^{2.} Gate charge for synchronous operation: see Appendix A: Power losses estimation

Table 5. Switching times

Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	Turn-on delay time Rise time Turn-off delay time Fall time	V_{DD} =15V, I_{D} =35A, R_{G} =4.7 Ω , V_{GS} =5V (see Figure 13)		21 95 19 15		ns ns ns ns

Table 6. Source drain diode

Symbol	Parameter	Test condictions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current				70	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				280	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} =35A, V _{GS} =0			1.3	٧
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 70A, di/dt=100A/ μ s, V_{DD} =20V, Tj=150°C (see Figure 18)		32 51 3.2		ns nC A

^{1.} Pulse width limited by safe operating area

^{2.} Pulsed: pulse duration = $300\mu s$, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

Figure 2. Thermal impedance

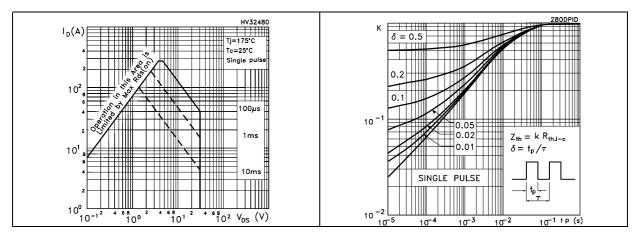


Figure 3. Output characterisics

Figure 4. Transfer characteristics

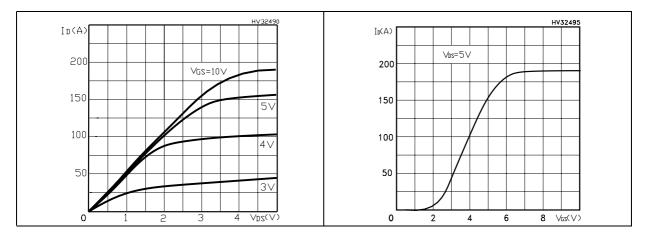
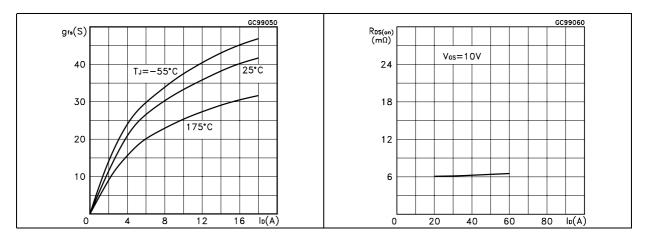


Figure 5. Transconductance

Figure 6. Static drain-source on resistance



577

Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

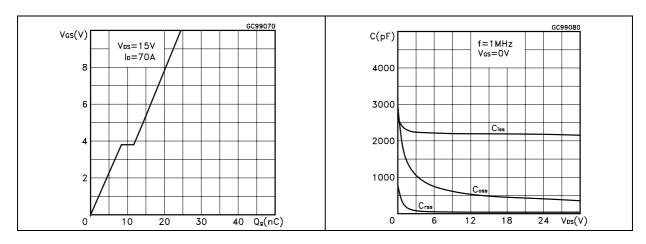


Figure 9. Normalized gate threshold voltage vs temperature

Figure 10. Normalized on resistance vs temperature

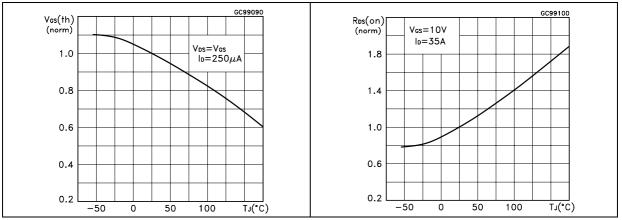
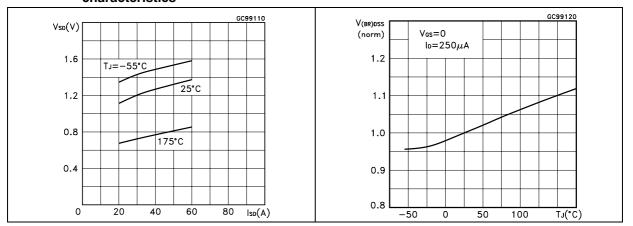


Figure 11. Source-drain diode forward characteristics

Figure 12. Normalized \mathbf{B}_{VDSS} vs temperature



3 Test circuit

Figure 13. Switching times test circuit for resistive load

Figure 14. Gate charge test circuit

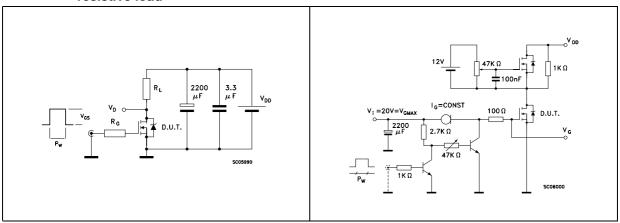


Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped inductive load test circuit

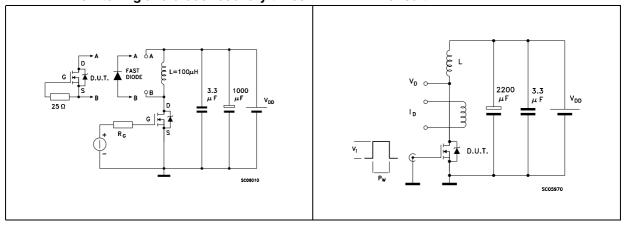
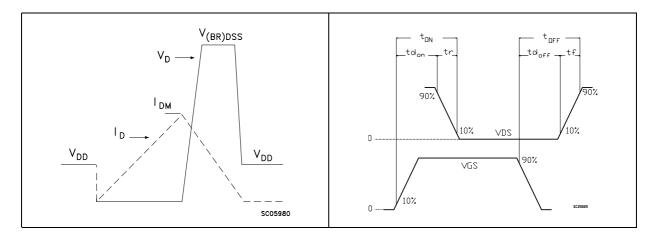


Figure 17. Unclamped inductive waveform

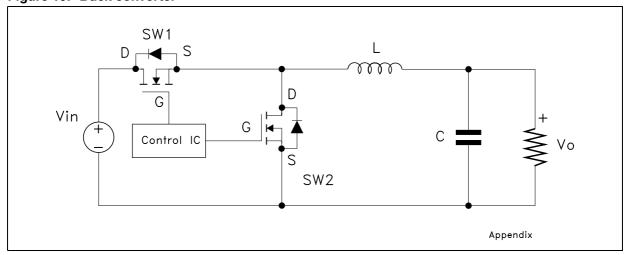
Figure 18. Switching time waveform



577

Appendix A Power losses estimation

Figure 19. Buck converter



The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

The low side (SW2) device requires:

- Very low R_{DS(on)} to reduce conduction losses
- Small Q_{qls} to reduce the gate charge losses
- Small C_{oss} to reduce losses due to output capacitance
- Small Q_{rr} to reduce losses on SW₁ during its turn-on
- The C_{gd}/C_{gs} ratio lower than V_{th}/V_{gg} ratio especially with low drain to source voltage to avoid the cross conduction phenomenon.

The high side (SW1) device requires:

- Small Rg and Lg to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Q_q to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses

		High side switch (SW1)	Low side switch (SW2)
P _{conduction}		$R_{DS(on)} \bullet I_L^2 \bullet \delta$	$R_{DS(on)} \bullet I_L^2 \bullet (1 - \delta)$
P _{switching}		$V_{in} \bullet (Q_{gsth(SW1)} + Q_{gd(SW1)}) \bullet f \bullet \frac{I_L}{I_g}$	Zero voltage switching
P _{diode}	Recovery	Not applicable	¹ V _{in} • Q _{rr(SW2)} • f
diode	Conduction	Not applicable	V _{f(SW2)} • I _L • t _{deadtime} • f
P _{gate(Qg)}		$Q_{g(SW1)} \bullet V_{gg} \bullet f$	$Q_{gls(SW2)} \bullet V_{gg} \bullet f$
P _{Qoss}		$\frac{V_{in} \bullet Q_{oss(SW1)} \bullet f}{2}$	$\frac{V_{in} \bullet Q_{oss(SW2)} \bullet f}{2}$

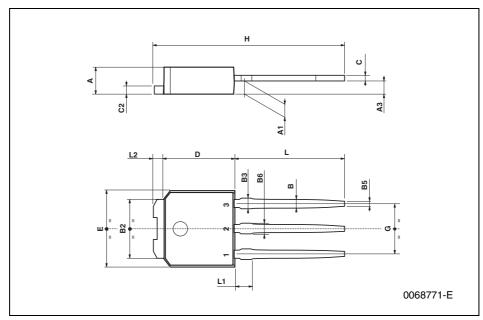
Parameter	Meaning
d	Duty-cycle
Q _{gsth}	Post threshold gate charge
Q _{gls}	Third quadrant gate charge
Pconduction	On state losses
Pswitching	On-off transition losses
Pdiode	Conduction and reverse recovery diode losses
Pgate	Gate driver losses
P _{Qoss}	Output capacitance losses

4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

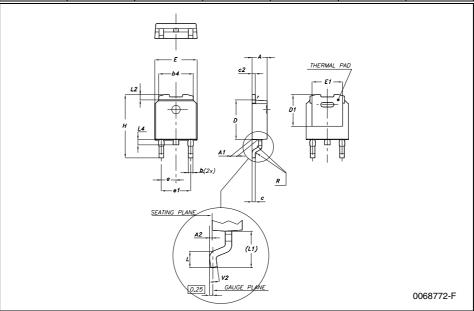
TO-251 (IPAK) MECHANICAL DATA

DIM.		mm			inch	
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
B3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
Е	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039



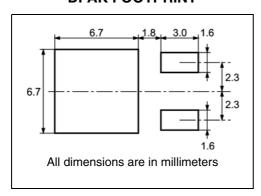
DPAK MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
E	6.4		6.6	0.252		0.260
E1		4.7			0.185	
е		2.28			0.090	
e1	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°

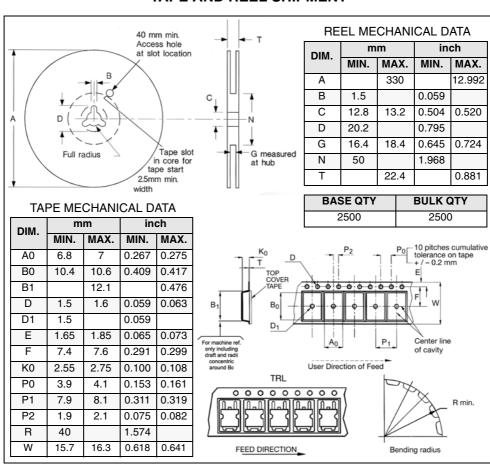


5 Packaging mechanical data

DPAK FOOTPRINT



TAPE AND REEL SHIPMENT



6 Revision history

Table 7. Revision history

Date	Revision	Changes
29-Jun-2006	1	First Release

Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZE REPRESENTATIVE OF ST, ST PRODUCTS ARE NOT DESIGNED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS, WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2006 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

4